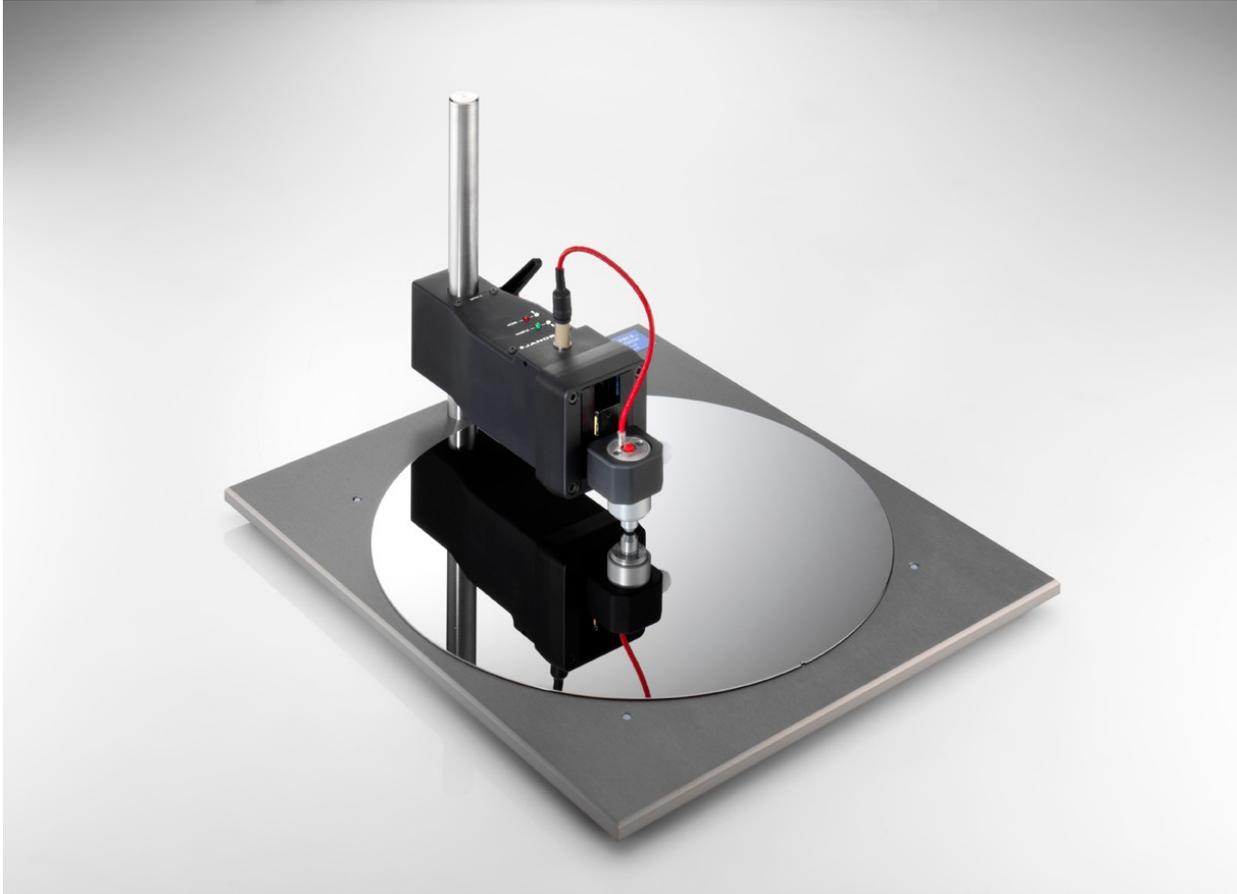


Automatic Multiheight Probe

JANDEL



Jandel Engineering Limited offers the Multiheight Probe station with an automatic Z motion (AFPP) for use in making four point probe measurements. The AFPP can be used for measuring a wide variety of samples from small sized thin layers and 300mm wafers up to ingots 250mm high (thicker samples can be accommodated on request).

The AFPP can be used stand alone with a supplied power adapter, or can be powered and operated by the Jandel RM3000 using a single lead connection between the two tools.

Automatic Multiheight Probe

Max. sample size	Samples up to 300mm diameter will fit on the measurement table
Max. sample thickness	Samples up to 250mm high can be measured (higher on request)
Auto-stop	Sample contact detected by force sensor
Manual Control	Home and Sample contact buttons situated on tool
Remote control	Jandel RM3000 can supply power and control sample contact

System Configuration

Component parts:

- A. Measurement Base - 1pc
- B. AFPP assembly - 1pc
- C. Multiheight Column - 1pc
- D. Four point probe head - 1pc
- E. Power cable - 1pc

System Footprint

- A. Multiheight Probe Base: 320mm W x 370mm L x 8mm H
- B. AFPP assembly: 64mm W x 215mm L x 67mm H
- C. Multiheight Column: 19mm diameter, 200mm L (up to 1m on request)

Type	Tip R	Force	Spacing
A	40u	100g	1mm
B	100u	100g	1mm
C	200u	100g	1mm
D	500u	70g	1mm
E	40u	200g	1.591mm
F	40u	100g	0.635mm
G	100u	100g	0.635mm
H	200u	100g	0.635mm



Type A-D and F-H are user adjustable in the range 60g-150g and supplied at

If you require any further information on the Automatic Multiheight Probe please contact us using the details below